

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/651,681	NAGASHIMA ET AL.	
Examiner	Art Unit	
Ryan Dare	2186	

	SEAR	CHED	
Class	Subclass	Date	Examiner
711	114	1/5/2006	RD
711	161	1/5/2006	RD
711	162	1/5/2006	RD

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY))
	DATE	EXMR
EAST(US-PGPUB; USPAT, USOCR; EPO; JPO; DERWENT; IBM_TDB)	1/5/2006	RD
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